# X-ray reflectivity from a thin film







Reflectivity: Continuum description of Material is enough.

Reality: "granular" description of a point lattice is required (otherwise there may well be reflectivity but no Bragg peaks)



If we look only at momentum transfers along z ("The specular path"), we can look at the scattered amplitude of light from a linear chain of atoms along z with a well defined truncation on top and bottom of the film.

Diffraction Amplitude from a linear chain  
1\*a   
2\*a   
3\*a   
f<sub>a</sub>  

$$A(q) = f_a \sum_{n=1}^{N_a} \exp(i * q * n * a)$$

$$= f_a * \frac{\exp(i * q * N_a * a) - 1}{\exp(i * q * a) - 1}$$

$$A * A^* = f_a^2 \left[ \frac{\sin(\frac{1}{2} * q * N_a * a)}{\sin(\frac{1}{2} * q * a)} \right]^2$$

# Diffraction amplitude from a linear chain as model for a thin crystalline film

 $\leftarrow \rightarrow$  D G

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#### PhDthesis

(contains an analytical treatment of diffraction from crystalline perfect thin films on pp42-56 and on pp 123-130)

$$\begin{split} I(Q) &= AA^* = \\ & 2\left[f_{a_1}^2 + f_{a_2}^2 + 2f_{a_1}f_{a_2}\cos\left(\phi_{a_1} - \phi_{a_2} - \frac{1}{2}aQ\right)\right] \left(\frac{\sin\left(\frac{1}{2}aN_aQ\right)}{\sin\left(\frac{1}{2}aQ\right)}\right) \\ &+ 2\left[f_{b_1}^2 + f_{b_2}^2 + 2f_{b_1}f_{b_2}\cos\left(\phi_{b_1} - \phi_{b_2} - \frac{1}{2}bQ\right)\right] \left(\frac{\sin\left(\frac{1}{2}bN_bQ\right)}{\sin\left(\frac{1}{2}bQ\right)}\right) \\ &+ 2\left[f_{a_1}f_{b_1}\cos\left(\phi_{a_1} - \phi_{b_1} - aQ - \frac{1}{2}aN_aQ - \frac{1}{2}bN_bQ\right) \\ &+ f_{a_1}f_{b_2}\cos\left(\phi_{a_1} - \phi_{b_2} - aQ - \frac{1}{2}aN_aQ - \frac{1}{2}bN_bQ - \frac{1}{2}bQ\right) \\ &+ f_{a_2}f_{b_1}\cos\left(\phi_{a_2} - \phi_{b_1} - \frac{1}{2}aQ - \frac{1}{2}aN_aQ - \frac{1}{2}bN_bQ\right) \\ &+ f_{a_2}f_{b_2}\cos\left(\phi_{a_2} - \phi_{b_2} - \frac{1}{2}aQ - \frac{1}{2}aN_aQ - \frac{1}{2}bN_bQ\right) \\ &+ \frac{\sin\left(\frac{1}{2}an_aQ\right)\sin\left(\frac{1}{2}bN_bQ\right)}{\sin\left(\frac{1}{2}bN_bQ\right)} \end{split}$$



The use of reciprocal space (=Fourier space) becomes practical when we look at periodic objects or well truncated objects



## From thin films to normal crystals



## **Differently shaped particles**



Again, the width on the central maximum depends only poorly on the particle shape, it is a very good reference to its average size D. This size is derived in a first approximation from the with  $\Delta Q$  of the Bragg peak in reciprocal space:

$$D = \frac{2\pi}{\Delta Q}$$
 or  $D * \Delta Q = 2\pi$ 

Philosophically looking at sharp Bragg peaks means determining the momentum of a photon with great precision. This is why a small  $\Delta Q$  (narrow width) must be related to an uncertainty of the crystals size it has been interacting with

Heisenberg:

$$\Delta x \Delta p \ge \frac{h}{2\pi} \quad (1)$$

FWHM<sub>BraggPeak</sub>~ 1/(Crystal size D)

*h*: Planck's constant



## Further quantification of peak properties: height and area



## Further quantification of peak properties: height and area

$$4 * A^* = f_a^{2} \left[ \frac{\sin(\frac{1}{2} * q * N_a * a)}{\sin(\frac{1}{2} * q * a)} \right]^2$$

2

Momentum transfer q(Å<sup>-1</sup>)

14

12

10

8

6

2

0

0

Electron units

#### Leads to an integrated intensity $\sim N_a$

It is obviously proportional to  $f_a^2$ , with  $f_a$  being the atomic scattering factor. Being the Fourier transform of the electron distribution of one atom,  $f_a$  depends itself on momentum transfer q (neglected on the previous pages)

## $f_a \sim Z$ (number of electrons)

We conclude that the peak intensity (Both, height and integrated one) are proportional to  $Z^2$  for the example of the monoatomic simple lattice considered here. For a more complex structure (anything that is not simple cubic elemental crystal, hence almost everything) this term must not be the atomic scattering factor, but the Fourier transform of the smallest periodic unit that builts up the crystal: the unit cell. The Fourier transform of the unit cell is called the structure factor  $F_{hkl}$ . It logically changes for every Bragg reflection, making the integrated Bragg diffraction intensities sensible to the structure of the unit cell.

$$A * A^* = F_{hkl}^2(q) \left[ \frac{\sin(\frac{1}{2} * q * N_a * a)}{\sin(\frac{1}{2} * q * a)} \right]$$

5

Atomic form factor of Silicon





Na

b=1

b=2

b=3

 $N_b$ 

$$\frac{r_{hkl}(q)}{\sin(1/2 * q_a * a)} = \frac{1}{\sin(1/2 * q_b * b)} \\ \frac{\sin(1/2 * q_c * N_c * c)}{\sin(1/2 * q_c * c)} \Big]^2$$

Remember: This oscillatory term leads to strong peaks whenever  $1/2 * q * N_a * a$  is an integer multiple of  $\pi$ , thus whenever  $q * a = n * 2\pi$ 

$$\begin{pmatrix} a \\ 0 \\ 0 \end{pmatrix} * \begin{pmatrix} q_x \\ q_y \\ q_z \end{pmatrix} = a * q_x = n * 2\pi$$

Or for a 3-dimensional crystal each of the products :

$$\mathbf{a} * q_x$$
,  $\mathbf{b} * q_y$ ,  $\mathbf{c} * q_z = \mathbf{n} * 2\pi$ 



# (Powder) Diffraction from a 3D crystal with a 3D unit cell



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# Examples for typical crystals and limits of these considerations for peak shapes

- As a start, we clearly have to differentiate between
- 1.)Powders
- 2.) (perfect) monocrystals
- 3.) Ideal imperfect crystals ("real" monocrystals) and perfect thin films

We have looked at 3.) with the example of a thin film or a "small crystal" goal: understanding peak *Intensities*. What about 2.) ?





From before we know that  $I_{hkl}$  (Peak)~ $I_0 * N_Z^2$  and  $I_{hkl}$  (Integrated)~ $I_0 * N_Z$ , if  $N_x$ ,  $N_y$ =const.

But, for reasons of Energy conservation  $I_{hkl}$  (Peak)< $I_0$ 

X-ray absorption and peak shapes:



 $\langle \rangle$ 

$$A = A_{o} e^{i(\omega t + \vec{k}\vec{r})}$$
Incoming plane wave
$$I_{0} = |A|_{t}^{2}$$

$$I_{0} = |A|_{t}^{2}$$

$$A_{hkl} = \sum_{k=1}^{N_{Z}} F_{hkl} e^{iq_{Z}z} * e^{-\mu z}$$

$$A_{hkl} = \sum_{1}^{N_Z} F_{hkl} e^{iq_z z} * e^{-\mu z}$$



### Real peak shapes of real perfect crystals

Under Bragg conditions in perfect crystals, Absorption does not limit the penetration depth...

 $A = A_o e^{i(\omega t + \vec{k}\vec{r})}$ Incoming plane wave

(hkl) Bragg reflection:

 $I_{hkl} = |A_{hkl}|^2$ 

 $I_0 = |A|_t^2$ Represented by "thickness"





...but a process called "extinction", i.e. the weakening of the electric field by scattering,

This is requires a complete treatment of the interaction between a plane wave with a lattice, including the presence of multiple scattering events. All derivations above and structure analysis as a whole depend on what is called the "kinematic scattering theory.

The strength of X-ray (and neutrons), as compared to electrons is that in general this assumption is valid

## Resolving (finding..., guessing...) Structures by X-ray diffraction

Distances, angles and "structure factors" make up the decisive information



Integrated Bragg Intensity=F<sub>hkl</sub>\*(crystallite size)\*(Incoming flux)\*(other factors....)